

SERIES IN OPTICS AND OPTOELECTRONICS

Thin-Film Optical Filters

Fourth Edition

H. Angus Macleod



CRC Press

Taylor & Francis Group

A TAYLOR & FRANCIS BOOK

Thin-Film Optical Filters

Fourth Edition

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H. Angus Macleod

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Contents

Preface to the Fourth Edition	209
Symbols and Abbreviations	219
1. Introduction	1
1.1 Early History	1
1.2 Twentieth-Century Science	3
References	10
2. Basic Theory	13
2.1 Maxwell's Equations	13
2.1.1 The Plane Wave	16
2.1.2 The Plane Wave in a Medium	16
2.1.3 The Plane Wave in a Medium	16
2.1.4 The Plane Wave in a Medium	16
2.1.5 The Plane Wave in a Medium	16
2.1.6 The Plane Wave in a Medium	16
2.1.7 The Plane Wave in a Medium	16
2.1.8 The Plane Wave in a Medium	16
2.1.9 The Plane Wave in a Medium	16
2.1.10 The Plane Wave in a Medium	16
2.1.11 The Plane Wave in a Medium	16
2.1.12 The Plane Wave in a Medium	16
2.1.13 The Plane Wave in a Medium	16
2.1.14 The Plane Wave in a Medium	16
2.1.15 The Plane Wave in a Medium	16
2.1.16 The Plane Wave in a Medium	16
2.1.17 The Plane Wave in a Medium	16
2.1.18 The Plane Wave in a Medium	16
2.1.19 The Plane Wave in a Medium	16
2.1.20 The Plane Wave in a Medium	16
2.1.21 The Plane Wave in a Medium	16
2.1.22 The Plane Wave in a Medium	16
2.1.23 The Plane Wave in a Medium	16
2.1.24 The Plane Wave in a Medium	16
2.1.25 The Plane Wave in a Medium	16
2.1.26 The Plane Wave in a Medium	16
2.1.27 The Plane Wave in a Medium	16
2.1.28 The Plane Wave in a Medium	16
2.1.29 The Plane Wave in a Medium	16
2.1.30 The Plane Wave in a Medium	16
2.1.31 The Plane Wave in a Medium	16
2.1.32 The Plane Wave in a Medium	16
2.1.33 The Plane Wave in a Medium	16
2.1.34 The Plane Wave in a Medium	16
2.1.35 The Plane Wave in a Medium	16
2.1.36 The Plane Wave in a Medium	16
2.1.37 The Plane Wave in a Medium	16
2.1.38 The Plane Wave in a Medium	16
2.1.39 The Plane Wave in a Medium	16
2.1.40 The Plane Wave in a Medium	16
2.1.41 The Plane Wave in a Medium	16
2.1.42 The Plane Wave in a Medium	16
2.1.43 The Plane Wave in a Medium	16
2.1.44 The Plane Wave in a Medium	16
2.1.45 The Plane Wave in a Medium	16
2.1.46 The Plane Wave in a Medium	16
2.1.47 The Plane Wave in a Medium	16
2.1.48 The Plane Wave in a Medium	16
2.1.49 The Plane Wave in a Medium	16
2.1.50 The Plane Wave in a Medium	16
2.1.51 The Plane Wave in a Medium	16
2.1.52 The Plane Wave in a Medium	16
2.1.53 The Plane Wave in a Medium	16
2.1.54 The Plane Wave in a Medium	16
2.1.55 The Plane Wave in a Medium	16
2.1.56 The Plane Wave in a Medium	16
2.1.57 The Plane Wave in a Medium	16
2.1.58 The Plane Wave in a Medium	16
2.1.59 The Plane Wave in a Medium	16
2.1.60 The Plane Wave in a Medium	16
2.1.61 The Plane Wave in a Medium	16
2.1.62 The Plane Wave in a Medium	16
2.1.63 The Plane Wave in a Medium	16
2.1.64 The Plane Wave in a Medium	16
2.1.65 The Plane Wave in a Medium	16
2.1.66 The Plane Wave in a Medium	16
2.1.67 The Plane Wave in a Medium	16
2.1.68 The Plane Wave in a Medium	16
2.1.69 The Plane Wave in a Medium	16
2.1.70 The Plane Wave in a Medium	16
2.1.71 The Plane Wave in a Medium	16
2.1.72 The Plane Wave in a Medium	16
2.1.73 The Plane Wave in a Medium	16
2.1.74 The Plane Wave in a Medium	16
2.1.75 The Plane Wave in a Medium	16
2.1.76 The Plane Wave in a Medium	16
2.1.77 The Plane Wave in a Medium	16
2.1.78 The Plane Wave in a Medium	16
2.1.79 The Plane Wave in a Medium	16
2.1.80 The Plane Wave in a Medium	16
2.1.81 The Plane Wave in a Medium	16
2.1.82 The Plane Wave in a Medium	16
2.1.83 The Plane Wave in a Medium	16
2.1.84 The Plane Wave in a Medium	16
2.1.85 The Plane Wave in a Medium	16
2.1.86 The Plane Wave in a Medium	16
2.1.87 The Plane Wave in a Medium	16
2.1.88 The Plane Wave in a Medium	16
2.1.89 The Plane Wave in a Medium	16
2.1.90 The Plane Wave in a Medium	16
2.1.91 The Plane Wave in a Medium	16
2.1.92 The Plane Wave in a Medium	16
2.1.93 The Plane Wave in a Medium	16
2.1.94 The Plane Wave in a Medium	16
2.1.95 The Plane Wave in a Medium	16
2.1.96 The Plane Wave in a Medium	16
2.1.97 The Plane Wave in a Medium	16
2.1.98 The Plane Wave in a Medium	16
2.1.99 The Plane Wave in a Medium	16
2.1.100 The Plane Wave in a Medium	16
2.2 The Simple Dielectric	18
2.2.1 Normal Incidence	23
2.2.2 Oblique Incidence	27
2.2.2.1 s-Polarized Light	28
2.2.2.2 p-Polarized Light	31
2.2.3 The Optical Admittance for Oblique Incidence	34
2.2.4 Normal Incidence in Absorbing Media	38
2.2.5 Oblique Incidence in Absorbing Media	56
2.3 The Reflectance of a Thin Film	41
2.4 The Reflectance of an Assembly of Thin Films	45
2.5 Reflectance, Transmittance, and Absorptance	48
2.6 Units	50
2.7 Summary of Important Results	52
2.8 Power and Transmittance	57
2.9 A Theorem on the Transmittance of a Thin-Film Assembly	60
2.10 Coherence	72
2.11 Increased Reflection at Two or More Interfaces	79
References	79
3. Theoretical Techniques	79
3.1 Quiver- and Half-Wave Optical Thicknesses	79
3.2 Admittance Loci	79
3.3 Electric Field and Power in the Admittance Diagram	80
3.4 The Vector Method	87
3.5 The Rayleigh Index	91
3.6 Alternative Method of Calculation	97
3.7 Smith's Method of Multilayer Design	98
3.8 The Inverse Case	98

Preface to the Fourth Edition

In some ways first editions are easier, or perhaps I should say, less difficult, to prepare than subsequent editions. By the time a fourth edition is required, there is a strong expectation among readers of the character and content of the book. Thus, the author must somehow try to maintain the style at the same time as bringing the book up to date. What to omit and what to include are very difficult questions. Modern optical coating design is virtually entirely performed by computer, frequently using automatic techniques. However, computers do not remove the need for understanding, and I think it is understanding that readers look for in the book. Also, I am conscious that a reader, having perhaps rejected an earlier edition in favor of a later and remembering something important in the earlier, might well expect to find it in the later. I made the decision, therefore, to retain most of the descriptions of the earlier design techniques because of their importance in understanding how designs work. Then, although some of the applications that I describe are rather old, nevertheless they do illustrate how optical coatings are incorporated into a system, and so I retained them. I have tried to incorporate a reasonable amount of new material throughout the book. I added a chapter on color because it is increasing in importance in optical coatings, and, although it is of largely academic interest, I could not resist a section on the effects of gain in optical coatings, because I find it a fascinating topic. Then I struggled with coatings for the soft x-ray region and, with some regret, decided not to include them at this time. It is the old design synthesis problem: one has to stop somewhere.

I am fortunate in my friends and colleagues who have helped me immeasurably with suggestions, advice, and, I have to admit it, corrections. The field of optical thin films has been very good to me. I cannot imagine a more friendly, supportive, and open group of people than the international optical thin-film community. It sets an example the rest of the world would do well to follow.

Thank you, all of you, my readers, publishers, friends, colleagues, family, and especially my wife, Ann.

H. Angus Macleod

Symbols and Abbreviations

The following list gives those more important symbols that have been used in at least several places in the text. We have tried as far as possible to create a consistent set of symbols, but there are several well-known and accepted symbols that are universally used in the field for certain quantities and changing them would probably lead to even greater confusion than would retaining them. This has meant that in some cases the same symbol is used in different places for different quantities. We hope the list will make it clear. Less important symbols, defined and used only in very short sections, have been omitted.

<i>A</i>	Absorptance; ratio of the power absorbed in the structure to the power incident on it.
<i>A</i>	Potential absorptance; quantity used in the calculation of the absorptance of coatings. It is equivalent to $(1 - \psi)$ where ψ is the potential transmittance.
<i>B</i>	Normalized total tangential electric field at an interface, usually the front interface of an assembly of layers. It is also used very briefly at the beginning of Chapter 2 as the magnetic induction.
<i>C</i>	Normalized total tangential magnetic field at an interface, usually the front interface of an assembly of layers.
d_q	Physical thickness of the q th layer in a thin film coating.
<i>E</i>	Electric vector in the electromagnetic field.
\bar{E}	Total tangential electric field amplitude, that is, the field parallel to the thin film boundaries.
\mathcal{E}	Electric field amplitude.
<i>E</i>	Equivalent admittance of a symmetrical arrangement of layers.
<i>F</i>	Function used in the theory of the Fabry–Perot interferometer.
\mathcal{F}	Finesse. The ratio of the separation of adjacent fringes to the half-width of the fringe in the Fabry–Perot interferometer.
<i>g</i>	$g = \lambda_0/\lambda = v/v_0$ sometimes called the relative wavelength, or the relative wave number, or the wavelength ratio. λ_0 and v_0 are the reference wavelength and reference wave number, respectively. The optical thicknesses of the layers in a coating are defined with respect to these quantities that are usually chosen to make the more important layers in the coating as close to quarter-waves as possible.
<i>H</i>	Magnetic vector in the electromagnetic field.

\mathcal{H}	Total tangential magnetic field amplitude, that is, the field parallel to the thin-film boundaries.
\mathcal{H}	Magnetic field amplitude.
H	Represents a quarter-wave of high index in shorthand notation.
I	Irradiance of the wave, that is power per unit area. Unfortunately, the standard SI symbol for irradiance is E but to use E would cause great confusion between irradiance and electric field. It is even more unfortunate that I is the SI symbol for intensity that is the power per unit solid angle from a point source. Doubly unfortunate is that the older definition of intensity is identical to the current definition of irradiance.
k	Extinction coefficient. The extinction coefficient denotes the presence of absorption. The complex refractive index, N , is given by $N = n - ik$.
L	Represents a quarter-wave of low index in shorthand notation.
M	Represents a quarter-wave of intermediate index in shorthand notation. Also used for a matrix element, or to indicate an array of matrix elements.
N	Denotes the complex refractive index, $n - ik$.
n	Refractive index or, sometimes, the real part of refractive index.
n^*	Effective index of a narrowband filter, that is, the index of an equivalent layer that yields a shift of its fringes in wavelength, by the same amount as the peak of the narrowband filter, when tilted with respect to the direction of incidence.
p	Packing density, that is the ratio of the solid volume of a film to its total volume.
p	p -Polarization, that is the polarization where the electric field direction is in the plane of incidence. It is sometimes known as TM for transverse magnetic.
R	Reflectance. The ratio at a boundary of the normal components of reflected and incident irradiance or, alternatively, the ratio of the total reflected beam power to the total incident beam power.
s	s -Polarization, that is the polarization where the electric field direction is normal to the plane of incidence. It is sometimes known as TE for transverse electric.
T	Transmittance. The ratio of the normal components of transmitted and incident irradiance or, alternatively, the ratio of the total transmitted beam power to the total incident beam power.
TE	See s for s -polarization.
TM	See p for p -polarization.

x, y, z	Coordinate axes. In the case of a thin film or surface the z -axis is usually taken positive into the surface in the direction of incidence. The x -axis is usually arranged in the plane of incidence and the x -, y -, and z -axes, in that order, make a right-handed set.
$\bar{x}, \bar{y}, \bar{z}$	Three color-matching functions that define the CIE 1931 Standard Colorimetric Observer.
X, Y, Z	Tristimulus values. They are the three basic responses defining a color.
x, y, z	Chromaticity coordinates, $X/(X + Y + Z)$, $Y/(X + Y + Z)$, $Z/(X + Y + Z)$. Usually z is omitted because they are normalized to add to unity.
$X + iZ$	Complex surface admittance.
y	Characteristic admittance of a material given in SI units (siemens) by $N\mathcal{Y}$, that is $(n - ik)\mathcal{Y}$ and in units of the admittance of free space, \mathcal{Y} , by N or $n - ik$.
Y	Surface admittance, that is the ratio of the total tangential components of magnetic and electric field at any surface parallel to the film boundaries. $Y = C/B$.
\mathcal{Y}	Admittance of free space (2.6544×10^{-3} S).
y_0	Characteristic admittance of the incident medium.
y_m or y_{sub}	Characteristic admittance of the emergent medium, or substrate.
α	Absorption coefficient, given by $4\pi k/\lambda$ usually in units of cm^{-1} .
α, β, γ	Three direction cosines, that is, the cosines of the angle the direction makes with the three coordinate axes.
β	Symbol for $2\pi kd/\lambda$ usually with reference to a metal.
γ	Equivalent phase thickness of a symmetrical arrangement of layers.
Δ	Relative retardation. It is given by $\varphi_p - \varphi_s \pm 180^\circ$ in reflection and $\varphi_p - \varphi_s$ in transmission, where the normal thin-film sign convention for φ_p is used.
Δ	η_p/η_s where η is the modified tilted admittance. The quantity is used in the design of polarization-free coatings.
δ	Phase thickness of a coating, given by $2\pi(n - ik)d/\lambda$.
ε	Indicates a small error in the discussion of tolerances, etc.
ε	Permittivity of a medium.
η	Tilted optical admittance.
ϑ	Angle of incidence.

κ	Sometimes called the wave number, κ is given by $2\pi(n - ik)/\lambda$ where λ is the free space wavelength. Note the confusing use of the term wave number. It is also applied to v .
λ	Wavelength of light. In the book, except at the very beginning of Chapter 2, it always indicates the wavelength in free space.
λ_0	Reference wavelength. The optical thicknesses of the layers in a coating are defined with respect to the reference wavelength that is usually chosen to make the more important layers in the coating as close to quarter-waves as possible.
v	Wave number. $v = 1/\lambda$ and is frequently expressed in units of cm^{-1} (also sometimes known as kayser. The SI unit is, strictly, inverse meters or m^{-1}).
v_0	Reference wave number, $1/\lambda_0$.
μ	Permeability. Used in early part of Chapter 2.
ρ	Amplitude reflection coefficient. Used also as electric charge density in early Chapter 2.
τ	Amplitude transmission coefficient.
φ	Phase difference, often in reflection or transmission.
ψ	Potential transmittance, $T/(1 - R)$ or the ratio of the quantities $\text{Re}(BC^*)$ evaluated at two different interfaces. It represents the power emerging from a system divided by the power entering and is unity if there is no loss.

Contents

Preface to the Fourth Edition	xiii
Symbols and Abbreviations	xv
1. Introduction	1
1.1 Early History.....	1
1.2 Thin-Film Filters.....	5
References	10
2. Basic Theory	13
2.1 Maxwell's Equations and Plane Electromagnetic Waves.....	13
2.1.1 The Poynting Vector.....	18
2.2 The Simple Boundary	21
2.2.1 Normal Incidence.....	23
2.2.2 Oblique Incidence	27
2.2.2.1 <i>p</i> -Polarized Light.....	28
2.2.2.2 <i>s</i> -Polarized Light.....	30
2.2.3 The Optical Admittance for Oblique Incidence	31
2.2.4 Normal Incidence in Absorbing Media.....	33
2.2.5 Oblique Incidence in Absorbing Media.....	38
2.3 The Reflectance of a Thin Film	42
2.4 The Reflectance of an Assembly of Thin Films	45
2.5 Reflectance, Transmittance, and Absorptance.....	48
2.6 Units.....	51
2.7 Summary of Important Results	52
2.8 Potential Transmittance	57
2.9 A Theorem on the Transmittance of a Thin-Film Assembly	60
2.10 Coherence.....	61
2.11 Incoherent Reflection at Two or More Surfaces	66
References	71
3. Theoretical Techniques	73
3.1 Quarter- and Half-Wave Optical Thicknesses.....	73
3.2 Admittance Loci.....	74
3.3 Electric Field and Losses in the Admittance Diagram.....	80
3.4 The Vector Method	87
3.5 The Herpin Index.....	89
3.6 Alternative Method of Calculation.....	89
3.7 Smith's Method of Multilayer Design	92
3.8 The Smith Chart.....	95

3.9	Reflection Circle Diagrams	97
	References	103
4.	Antireflection Coatings	105
4.1	Antireflection Coatings on High-Index Substrates	106
4.1.1	The Single-Layer Antireflection Coating	106
4.1.2	Double-Layer Antireflection Coatings	112
4.1.3	Multilayer Coatings	121
4.2	Antireflection Coatings on Low-Index Substrates	129
4.2.1	The Single-Layer Antireflection Coating	130
4.2.2	Two-Layer Antireflection Coatings	130
4.2.3	Multilayer Antireflection Coatings	140
4.3	Equivalent Layers	156
4.4	Antireflection Coatings for Two Zeros	168
4.5	Antireflection Coatings for the Visible and the Infrared	172
4.6	Inhomogeneous Layers	179
4.7	Further Information	182
	References	183
5.	Neutral Mirrors and Beam Splitters	185
5.1	High-Reflectance Mirror Coatings	185
5.1.1	Metallic Layers	185
5.1.2	Protection of Metal Films	187
5.1.3	Overall System Performance, Enhanced Reflectance	193
5.1.4	Reflecting Coatings for the Ultraviolet	196
5.2	Neutral Beam Splitters	198
5.2.1	Beam Splitters Using Metallic Layers	198
5.2.2	Beam Splitters Using Dielectric Layers	201
5.3	Neutral-Density Filters	205
	References	207
6.	Multilayer High-Reflectance Coatings	209
6.1	The Fabry-Perot Interferometer	209
6.2	Multilayer Dielectric Coatings	215
6.2.1	All-Dielectric Multilayers with Extended High-Reflectance Zones	225
6.2.2	Coating Uniformity Requirements	230
6.3	Losses	234
	References	238
7.	Edge Filters	241
7.1	Thin-Film Absorption Filters	241
7.2	Interference Edge Filters	242
7.2.1	The Quarter-Wave Stack	243

7.2.2	Symmetrical Multilayers and the Herpin Index	244
7.2.2.1	Application of the Herpin Index to the Quarter-Wave Stack	248
7.2.2.2	Application of the Herpin Index to Multilayers of Other Than Quarter-Waves.....	253
7.2.3	Performance Calculations.....	256
7.2.3.1	Transmission at the Edge of a Stop Band.....	256
7.2.3.2	Transmission in the Center of a Stop Band	258
7.2.3.3	Transmission in the Pass Band.....	260
7.2.3.4	Reduction of Pass-Band Ripple	262
7.2.3.5	Summary of Design Procedure so Far	265
7.2.3.6	More Advanced Procedures for Eliminating Ripple	266
7.2.3.7	Practical Filters	281
7.2.3.8	Extending the Rejection Zone by Interference Methods.....	283
7.2.3.9	Extending the Transmission Zone.....	287
7.2.3.10	Reducing the Transmission Zone	295
7.2.3.11	Edge Steepness.....	296
	References	297
8.	Band-Pass Filters.....	299
8.1	Broadband-Pass Filters	299
8.2	Narrowband Filters.....	302
8.2.1	The Metal-Dielectric Single-Cavity Filter	302
8.2.2	The All-Dielectric Single-Cavity Filter	310
8.2.2.1	Case 1: Even Number ($2x$) of Layers	313
8.2.2.2	Case II: Odd Number ($2x + 1$) of Layers	315
8.2.2.3	Phase Shift: Case I.....	316
8.2.2.4	Phase Shift: Case II.....	317
8.2.3	The Solid Etalon Filter.....	325
8.2.4	The Effect of Varying the Angle of Incidence.....	329
8.2.4.1	Simple Tilts in Collimated Light	329
8.2.4.2	Case I: High-Index Cavities	332
8.2.4.3	Case II: Low-Index Cavities	333
8.2.4.4	Effect of an Incident Cone of Light	335
8.2.5	Sideband Blocking	341
8.3	Multiple Cavity Filters.....	342
8.3.1	Thelen's Method of Analysis.....	349
8.4	Higher Performance in Multiple-Cavity Filters.....	356
8.4.1	Effect of Tilting.....	364
8.4.2	Losses in Multiple Cavity Filters	367
8.4.2.1	Case I: High-Index Cavities	368
8.4.2.2	Case II: Low-Index Cavities	369
8.4.3	Further Information	369

8.5	Phase Dispersion Filter.....	370
8.6	Multiple Cavity Metal–Dielectric Filters	377
8.6.1	The Induced-Transmission Filter	380
8.6.1.1	Potential Transmittance.....	381
8.6.1.2	Optimum Exit Admittance	382
8.6.1.3	Maximum Potential Transmittance.....	384
8.6.1.4	Matching Stack	384
8.6.1.5	Front Surface Equivalent Admittance	386
8.6.2	Examples of Filter Designs	386
8.7	Measured Filter Performance.....	396
	References	399
9.	Tilted Coatings.....	403
9.1	Modified Admittances and the Tilted Admittance Diagram.....	403
9.2	Application of the Admittance Diagram.....	411
9.3	Polarizers.....	425
9.3.1	The Brewster Angle Polarizing Beam Splitter	425
9.3.2	Plate Polarizer.....	430
9.3.3	Cube Polarizers	431
9.4	Nonpolarizing Coatings.....	431
9.4.1	Edge Filters at Intermediate Angle of Incidence	432
9.4.2	Reflecting Coatings at Very High Angles of Incidence	437
9.4.3	Edge Filters at Very High Angles of Incidence.....	441
9.5	Antireflection Coatings.....	442
9.5.1	<i>p</i> -Polarization Only.....	442
9.5.2	<i>s</i> -Polarization Only	443
9.5.3	<i>s</i> - and <i>p</i> -Polarization Together	444
9.6	Retarders	447
9.6.1	The Ellipsometric Parameters and Relative Retardation	447
9.6.2	Series of Coated Surfaces	448
9.6.3	Retarders	449
9.6.4	Simple Retarders.....	451
9.6.5	Multilayer Retarders at One Wavelength.....	455
9.6.6	Multilayer Retarders for a Range of Wavelengths.....	459
9.7	Optical Tunnel Filters.....	464
	References	467
10.	Color in Optical Coatings.....	471
10.1	Color Definition.....	471
10.2	The 1964 Supplementary Colorimetric Observer	478
10.3	Metamerism.....	479
10.4	Other Color Spaces.....	480
10.5	Hue and Chroma.....	481

10.6	Brightness and Optimal Stimuli.....	482
10.7	Colored Fringes.....	485
	References	487
11.	Production Methods and Thin-Film Materials.....	489
11.1	The Production of Thin Films.....	490
11.1.1	Thermal Evaporation.....	491
11.1.2	Energetic Processes.....	501
11.1.3	Other Processes.....	513
11.1.4	Baking.....	517
11.2	Measurement of the Optical Properties.....	520
11.3	Measurement of the Mechanical Properties	540
11.4	Toxicity.....	550
11.5	Summary of Some Properties of Common Materials.....	551
	References	561
12.	Factors Affecting Layer and Coating Properties.....	569
12.1	Microstructure and Thin-Film Behavior.....	569
12.2	Sensitivity to Contamination	584
	References	592
13.	Layer Uniformity and Thickness Monitoring.....	595
13.1	Uniformity	595
13.1.1	Flat Plate.....	597
13.1.2	Spherical Surface.....	598
13.1.3	Rotating Substrates.....	598
13.1.4	Use of Masks.....	603
13.2	Substrate Preparation	604
13.3	Thickness Monitoring and Control.....	607
13.3.1	Optical Monitoring Techniques.....	608
13.3.2	The Quartz-Crystal Monitor	618
13.3.3	Monitoring by Deposition Time	620
13.4	Tolerances.....	621
	References	636
14.	Specification of Filters and Environmental Effects.....	641
14.1	Optical Properties.....	641
14.1.1	Performance Specification	641
14.1.2	Manufacturing Specification.....	644
14.1.3	Test Specification.....	644
14.2	Physical Properties.....	648
14.2.1	Abrasion Resistance.....	648
14.2.2	Adhesion	651
14.2.3	Environmental Resistance	652
	References	653

15. System Considerations: Applications of Filters and Coatings.....	655
15.1 Potential Energy Grasp of Interference Filters	659
15.2 Narrowband Filters in Astronomy	665
15.3 Atmospheric Temperature Sounding.....	670
15.4 Order Sorting Filters for Grating Spectrometers.....	679
15.5 Glare Suppression Filters and Coatings	691
15.6 Some Coatings Involving Metal Layers.....	695
15.6.1 Electrode Films for Schottky-Barrier Photodiodes	695
15.6.2 Spectrally Selective Coatings for Photothermal Solar Energy Conversion	698
15.6.3 Heat Reflecting Metal-Dielectric Coatings	703
References	705
16. Other Topics.....	707
16.1 Rugate Filters	707
16.2 Ultrafast Coatings	718
16.3 Automatic Methods	729
16.4 Gain in Optical Coatings	740
16.4.1 Oblique Incidence	744
16.5 Photonic Crystals	748
16.5.1 What Is a Photonic Crystal?	750
16.5.2 Two-Dimensional Photonic Crystals	750
16.5.3 One-Dimensional Photonic Crystals	751
References	756
17. Characteristics of Thin-Film Dielectric Materials	759
References	766
Bibliography.....	771
Index.....	773